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U.S. UTILITY Patent Application					
O.I.P.E. SCAPHED L M2 Q.A. 4	1	PATENT DATE			

APPLICATION NO. 09/942907	CONT/PRIOR F	CLASS 438	SUBCLASS 424	ART UNIT	EXAMINER TILLINGS
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Method for fabricating semiconductor device

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TERMINAL		DRAWINGS		CLAIMS ALLOWED		
DISCLAIMER	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.	
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subsequent to (date) has been disclaimed.	(Assistant	Examiner)	(Date)			
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